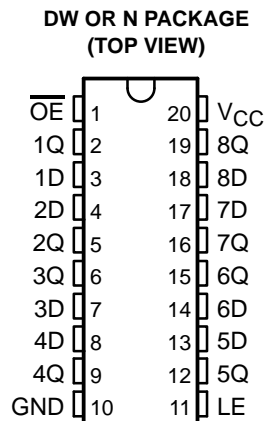


SN64BCT373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

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- State-of-the-Art BiCMOS Design Significantly Reduces I_{CCZ}
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- High-Impedance State During Power Up and Power Down
- 3-State True Outputs Drive Bus Lines or Buffer-Memory Address Registers
- Full Parallel Access for Loading
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic 300-mil DIPs (N)



description

This 8-bit latch features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches of the SN64BCT373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When the enable is taken low, the Q outputs are latched at the levels that were set up at the D inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state the outputs neither load nor drive the bus lines significantly. The high-impedance impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

The output-enable (\overline{OE}) does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are off.

The outputs are in a high-impedance state during power up and power down while the supply voltage is less than approximately 3 V.

The SN64BCT373 is characterized for operation from -40°C to 85°C and 0°C to 70°C .

FUNCTION TABLE
(each latch)

INPUTS			OUTPUT Q
\overline{OE}	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q_0
H	X	X	Z

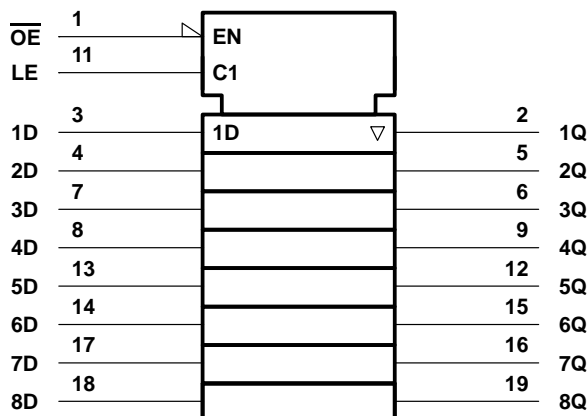
SN64BCT373

OCTAL TRANSPARENT D-TYPE LATCH

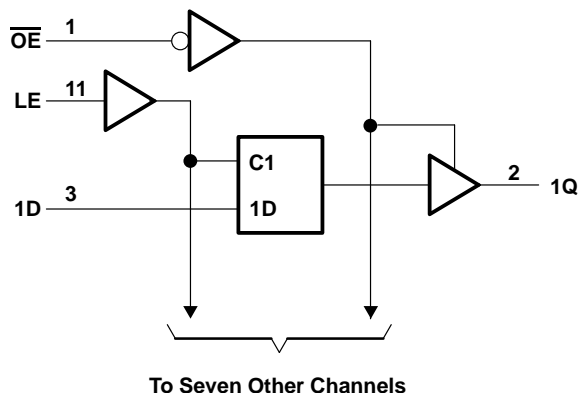
WITH 3-STATE OUTPUTS

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logic symbol†



logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the disabled or power-off state, V_O	–0.5 V to 5.5 V
Voltage range applied to any output in the high state, V_O	–0.5 V to V_{CC}
Input clamp current, I_{IK} ($V_I < 0$)	–30 mA
Current into any output in the low state, I_O	128 mA
Operating free-air temperature range	–40°C to 85°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			–18	mA
I_{OH}	High-level output current			–15	mA
I_{OL}	Low-level output current			64	mA
$\Delta t/\Delta V_{CC}$	Power-up ramp rate	2			$\mu s/V$
T_A	Operating free-air temperature	–40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

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OCTAL TRANSPARENT D-TYPE LATCH
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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IK}	$V_{CC} = 4.5 \text{ V}$,	$I_I = -18 \text{ mA}$			-1.2	V
V_{OH}	$V_{CC} = 4.5 \text{ V}$	$I_{OH} = -3 \text{ mA}$	2.4	3.3		V
		$I_{OH} = -15 \text{ mA}$	2	3.1		
V_{OL}	$V_{CC} = 4.5 \text{ V}$,	$I_{OL} = 64 \text{ mA}$	0.42	0.55		V
I_I	$V_{CC} = 5.5 \text{ V}$,	$V_I = 5.5 \text{ V}$			0.4	mA
I_{IH}	$V_{CC} = 5.5 \text{ V}$,	$V_I = 2.7 \text{ V}$			20	μA
I_{IL}	$V_{CC} = 5.5 \text{ V}$,	$V_I = 0.5 \text{ V}$			-0.6	mA
I_{OS}^\ddagger	$V_{CC} = 5.5 \text{ V}$,	$V_O = 0$	-100		-225	mA
I_{OZ}	$V_{CC} = 0 \text{ to } 2.3 \text{ V}$ (power up)	$V_O = 2.7 \text{ V or } 0.5 \text{ V}$, $\overline{OE} = 0.8 \text{ V}$			± 50	μA
	$V_{CC} = 1.8 \text{ V to } 0$ (power down)				± 50	
I_{OZH}	$V_{CC} = 5.5 \text{ V}$,	$V_O = 2.7 \text{ V}$			50	μA
I_{OZL}	$V_{CC} = 5.5 \text{ V}$,	$V_O = 0.5 \text{ V}$			-50	μA
I_{CCL}	$V_{CC} = 5.5 \text{ V}$,	Outputs open		37	60	mA
I_{CCH}	$V_{CC} = 5.5 \text{ V}$,	Outputs open		2	5	mA
I_{CCZ}	$V_{CC} = 5.5 \text{ V}$,	Outputs open		5	8	mA
C_i	$V_{CC} = 5 \text{ V}$,	$V_I = 2.5 \text{ V or } 0.5 \text{ V}$		6		pF
C_o	$V_{CC} = 5 \text{ V}$,	$V_O = 2.5 \text{ V or } 0.5 \text{ V}$		11		pF

† All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$.

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

timing requirements over recommended range of supply voltage (unless otherwise noted)

		V _{CC} = 5 V, T _A = 25°C		V _{CC} = 4.5 V to 5.5 V				UNIT
				T _A = -40°C to 85°C		T _A = 0°C to 70°C		
		MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high	7.5		7.5		7.5		ns
t _{su}	Setup time, data before LE↓	2		2		2		ns
t _h	Hold time, data after LE↓	5.5		5.5		5.5		ns

switching characteristics over recommended range of supply voltage, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$			$T_A = -40^\circ\text{C}$ to 85°C		$T_A = 0^\circ\text{C}$ to 70°C		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	D	Q	2	5.9	7.7	1.5	10.1	2	9.3	ns
t_{PHL}			2	6.7	8.5	1	10.3	1.5	9.5	
t_{PLH}	LE	Q	2	6.2	8.2	2	10.1	2	9.3	ns
t_{PHL}			2	5.9	7.8	2	9.2	2	8.8	
t_{PZH}	\overline{OE}	Q	1	7.8	9.6	1	12.3	1	11.8	ns
t_{PZL}			1	8.2	10.2	1	12.5	1	12	
t_{PHZ}	\overline{OE}	Q	1	4.9	6.6	1	7.4	1	7	ns
t_{PLZ}			1	5	6.7	1	8.1	1	7.4	

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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